


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/062,408	YAMAUCHI ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Prenell P. Jones	2668	

SEARCHED			
Class	Subclass	Date	Examiner
370	390 240 232 237 338 352 400 420 392 238	11/15/2005	PJ
709	203-206 224		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
West Search Tool US and PGPUb database  Non-patent Literature IEEE and ACM databases  www.alltheweb.com	11/15/2005	PJ